

INTERNATIONAL SEARCH REPORT

 Intern: ☐ of Application No
 PCT/IB2005/050347

A. CLASSIFICATION OF SUBJECT MATTER
 IPC 7 G01R31/316 H01L23/544

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 G01R H01L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, WPI Data

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	DE MUNARI I ET AL: "A test pattern for three-dimensional latch-up analysis" MICROELECTRONIC TEST STRUCTURES, 1993. ICMTS 1993. PROCEEDINGS OF THE 1993 INTERNATIONAL CONFERENCE ON SITGES, SPAIN 22-25 MARCH 1993, NEW YORK, NY, USA, IEEE, US, 22 March 1993 (1993-03-22), pages 103-109, XP010107420 ISBN: 0-7803-0857-3 figures 1,3,5,6 abstract page 105, column 2, paragraph 3 - page 108, column 2, paragraph 1 ----- -/--	1-13

☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

* Special categories of cited documents:

- *A* document defining the general state of the art which is not considered to be of particular relevance
- *E* earlier document but published on or after the international filing date
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- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

- *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
- *&* document member of the same patent family

Date of the actual completion of the international search

22 April 2005

Date of mailing of the international search report

29/04/2005

Name and mailing address of the ISA

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	MUNARI DE I ET AL: "DESIGN AND SIMULATION OF A TEST PATTERN FOR THREE-DIMENSIONAL LATCH-UP ANALYSIS" MICROELECTRONICS JOURNAL, MACKINTOSH PUBLICATIONS LTD. LUTON, GB, vol. 24, no. 7, 1 November 1993 (1993-11-01), pages 759-771, XP000411878 ISSN: 0026-2692 figures 2,3,7,13,14 abstract page 760, column 2, paragraph 3 page 761, column 1, paragraph 1 - column 2, paragraph 1 page 766, column 1, paragraph 2 - page 770, column 1, paragraph 1	1-7
A	YONG-HA SONG ET AL: "The reliability issues on ASIC/memory integration by SiP (system-in-package) technology" IEEE, 17 September 2003 (2003-09-17), pages 7-10, XP010665812 page 9, column 2, paragraph 2 - page 10, column 1, paragraph 3	6,7
A	DE 101 62 542 A (INFINEON TECHNOLOGIES AG) 10 April 2003 (2003-04-10) figures 1-5 abstract paragraph '0007! paragraph '0012! paragraph '0018! paragraph '0057!	10
A	AOKI T ED - INSTITUTE OF ELECTRICAL AND ELECTRONICS ENGINEERS: "A new latch-up test structure for practical design methodology for internal circuits in the standard cell-based CMOS/BiCMOS LSIs" PROCEEDINGS OF THE INTERNATIONAL CONFERENCE ON MICROELECTRONIC TEST STRUCTURES (ICMTS). SAN DIEGO, MAR. 16 - 19, 1992, NEW YORK, IEEE, US, 16 March 1992 (1992-03-16), pages 18-23, XP010059383 ISBN: 0-7803-0535-3 figures 1-3,6,7 abstract page 18, column 1, paragraph 2 - page 19, column 1, paragraph 2	1,8
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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	ROBERTO MENOZZI ET AL: "Effects of the Interaction of Neighboring Structures on the Latch-up Behavior of C-MOS IC's" IEEE TRANSACTIONS ON ELECTRON DEVICES, vol. 38, no. 8, August 1991 (1991-08), pages 1978-1981, XP002290985 ISSN: 0018-9383 figures 1-4 page 1978, column 1, paragraph 2 - page 1979, column 1, paragraph 2 -----	1,8
A	ROBERTO MENOZZI ET AL: "Layout Dependence of CMOS Latchup" IEEE TRANSACTIONS ON ELECTRON DEVICES, vol. 35, no. 11, November 1988 (1988-11), pages 1892-1901, XP002290986 ISSN: 0018-9383 figures 2,4,5,7,10-12,14,15 table 1 page 1892, column 1, paragraph 2 - page 1893, column 2, paragraph 3 -----	1,8

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Information on patent family members

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PCT/IB2005/050347

Patent document cited in search report	Publication date	Patent family member(s)	Publication date
DE 10162542 A	10-04-2003	DE 10162542 A1	10-04-2003
		WO 03052824 A2	26-06-2003
		EP 1456881 A2	15-09-2004
		US 2005003564 A1	06-01-2005
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